

Advanced LIGO Photodiode Development

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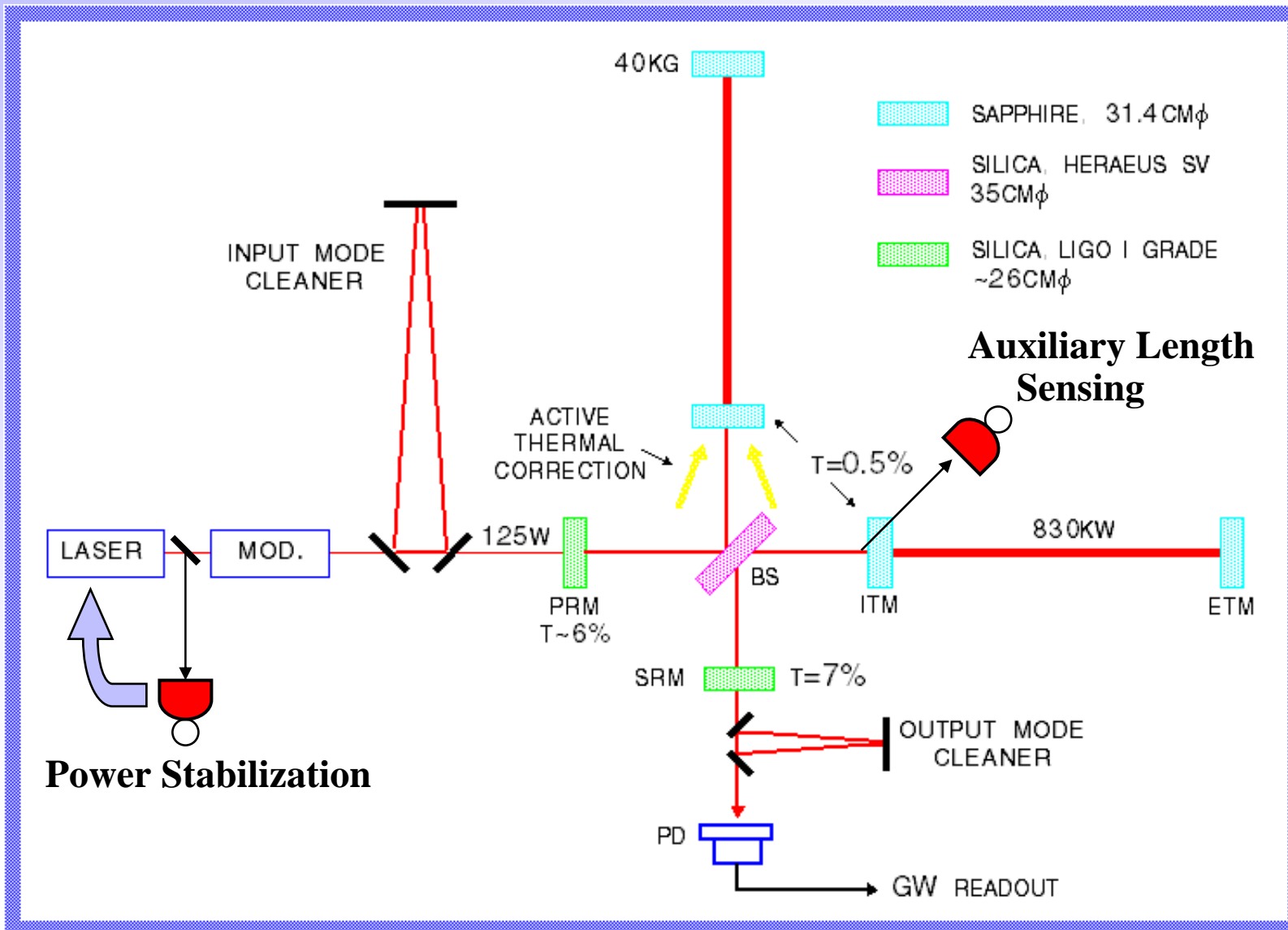
Solid State Research Lab, Stanford University

LSC Meeting - LLO

March 22nd, 2005

- **AdLIGO Photodiode Specifications**
- **Device Results**
- **Damage Threshold**
- **AdLIGO Devices**
- **Future Directions**

Advanced LIGO Schematic



Photodiode Specifications



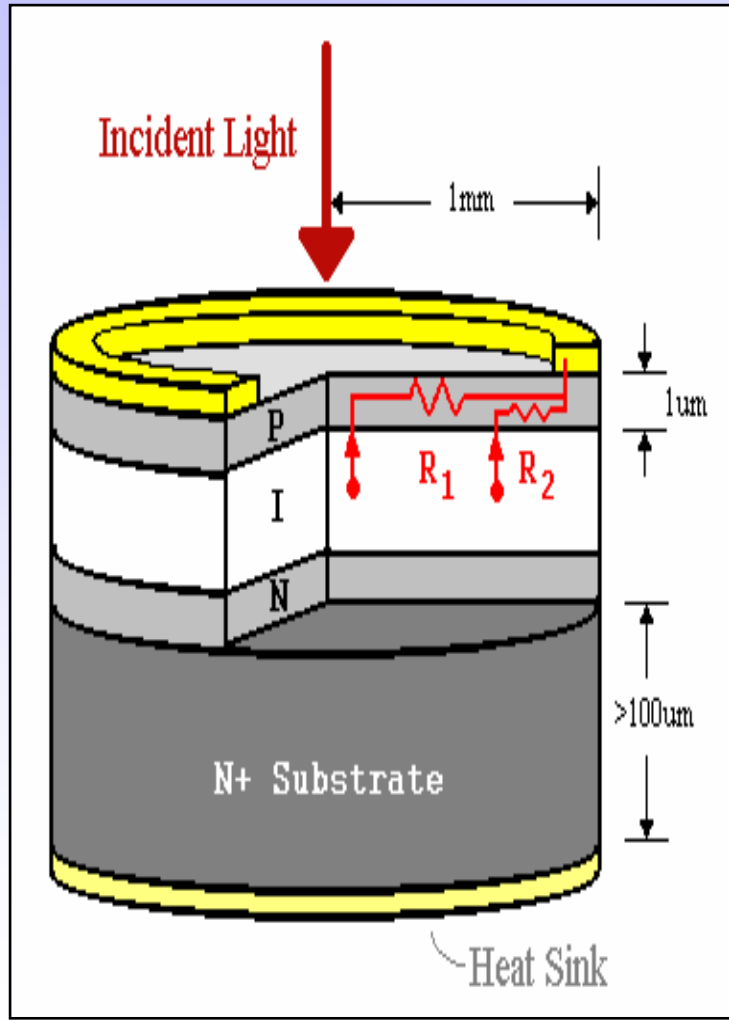
	LIGO I		Advanced LIGO	
Detector	Bank of 6PDs	Power Stabilization	Aux. Length (RF) Detection	DC - GW Channel
Steady-State "Power"	0.6 W	200 ~ 300 mA	10 - 100 mW	30 mW
Operating Frequency	~29 MHz	100 kHz	200 MHz	100 kHz
Quantum Efficiency	> 80%	η	> 80%	> 90%

$(300\text{mA}) / (0.868\text{A/W} * 0.90 \text{ QE}) = 385\text{mW}$

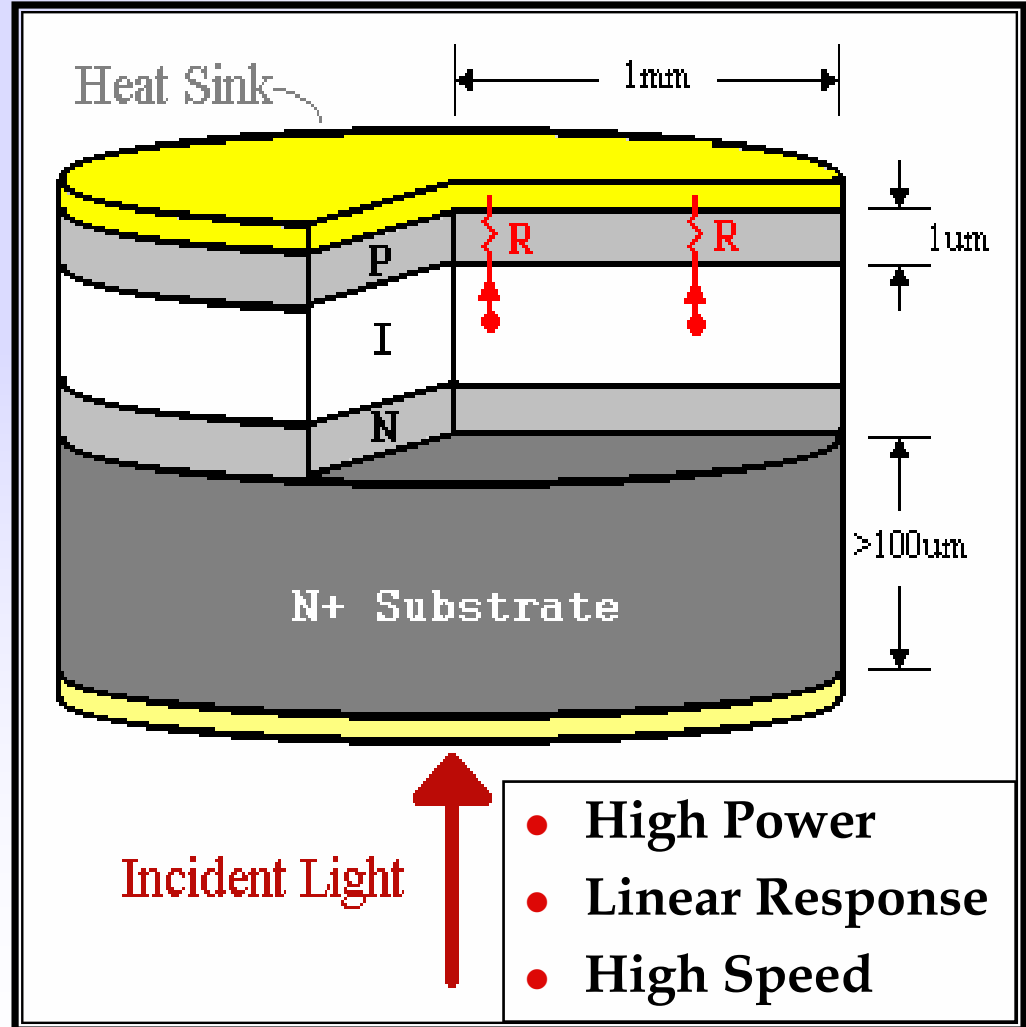
Resonating Tank Circuit

Trades w/ Sensitivity

Rear-Illuminated PD Advantages



Conventional PD



- High Power
- Linear Response
- High Speed

Adv. LIGO Rear-Illuminated PD

Materials Analysis – InGaAs/GaAs vs. GaInNAs/GaAs



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- X-Ray Diffraction

- Transmission Electron Microscopy

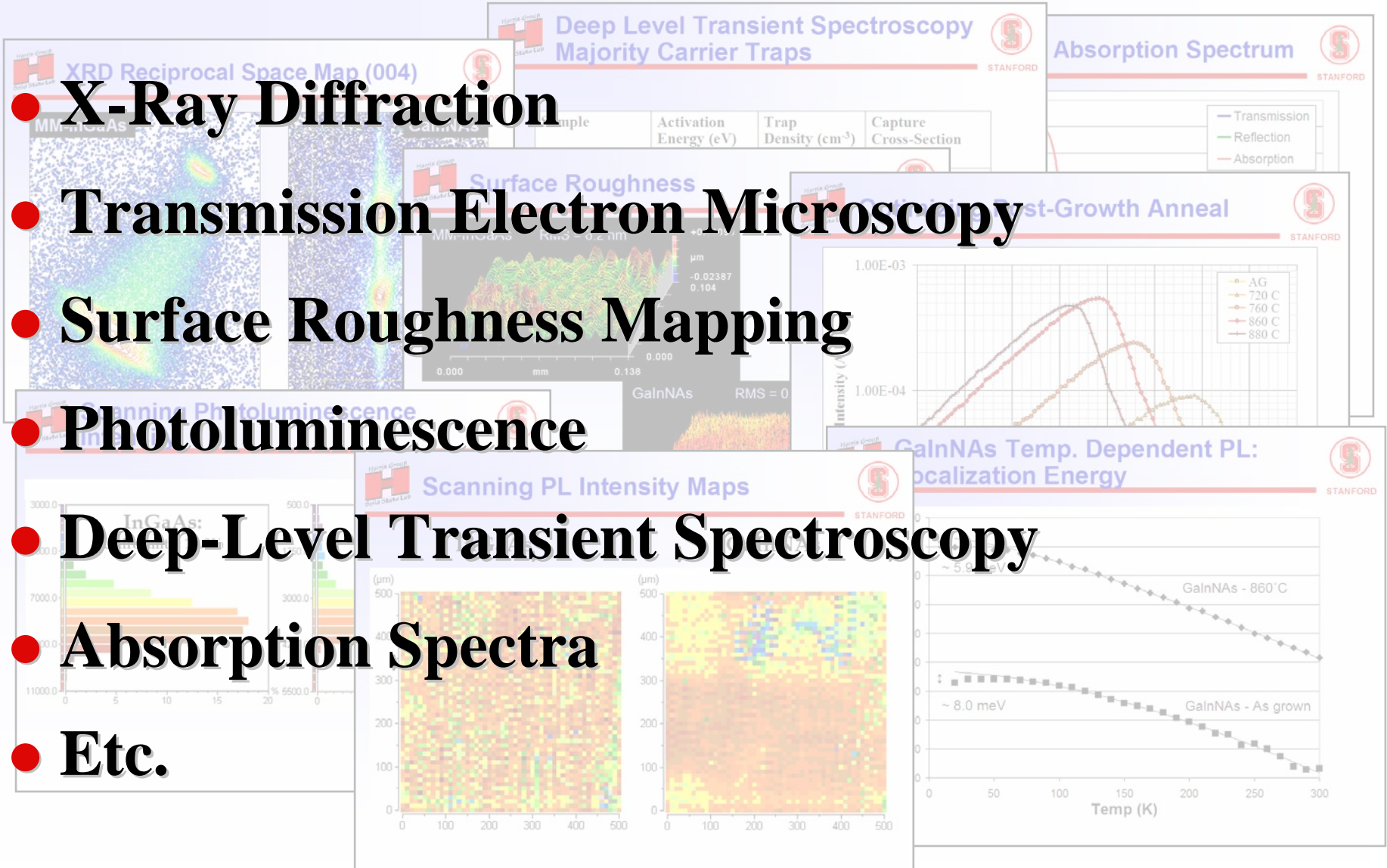
- Surface Roughness Mapping

- Photoluminescence

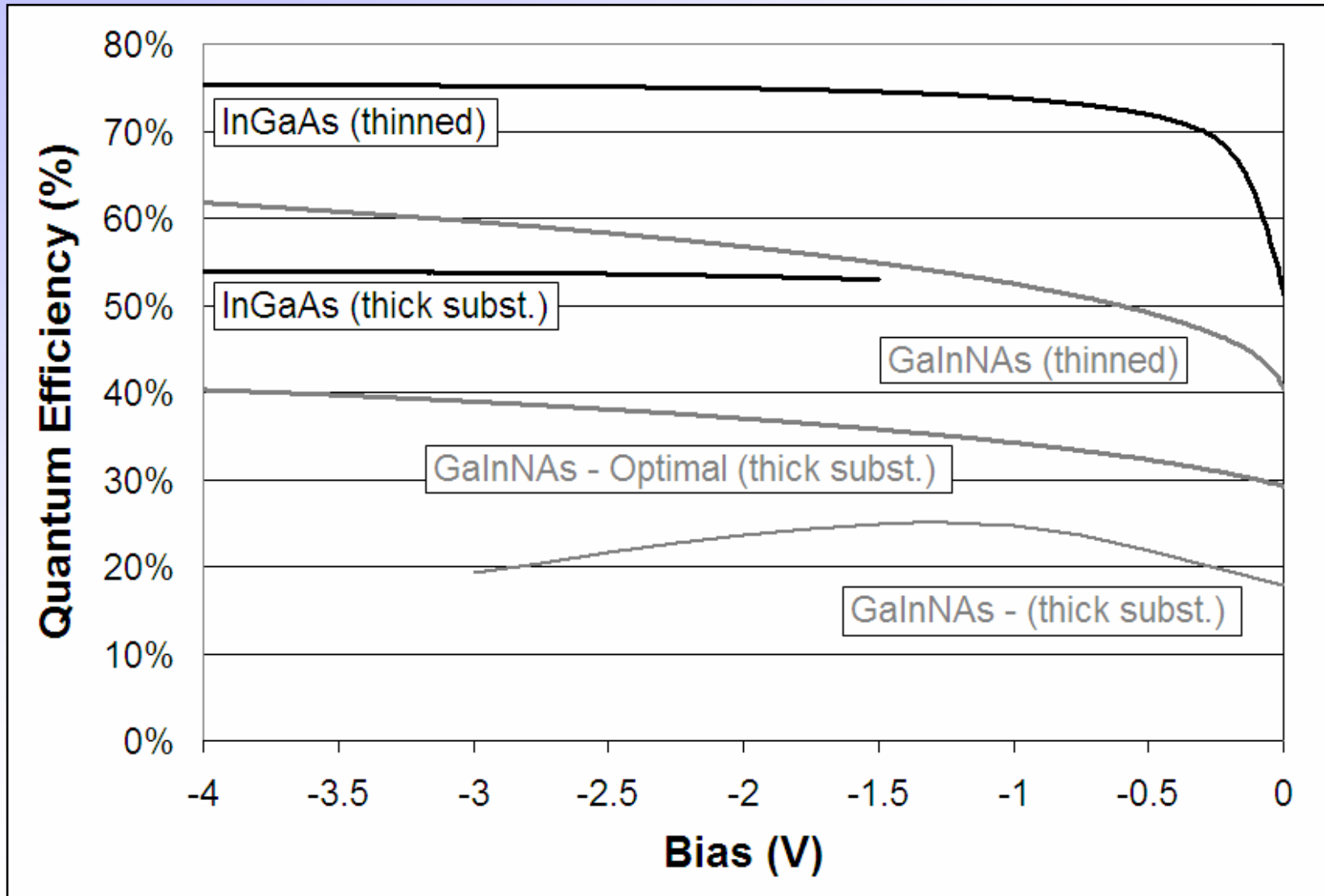
- Deep-Level Transient Spectroscopy

- Absorption Spectra

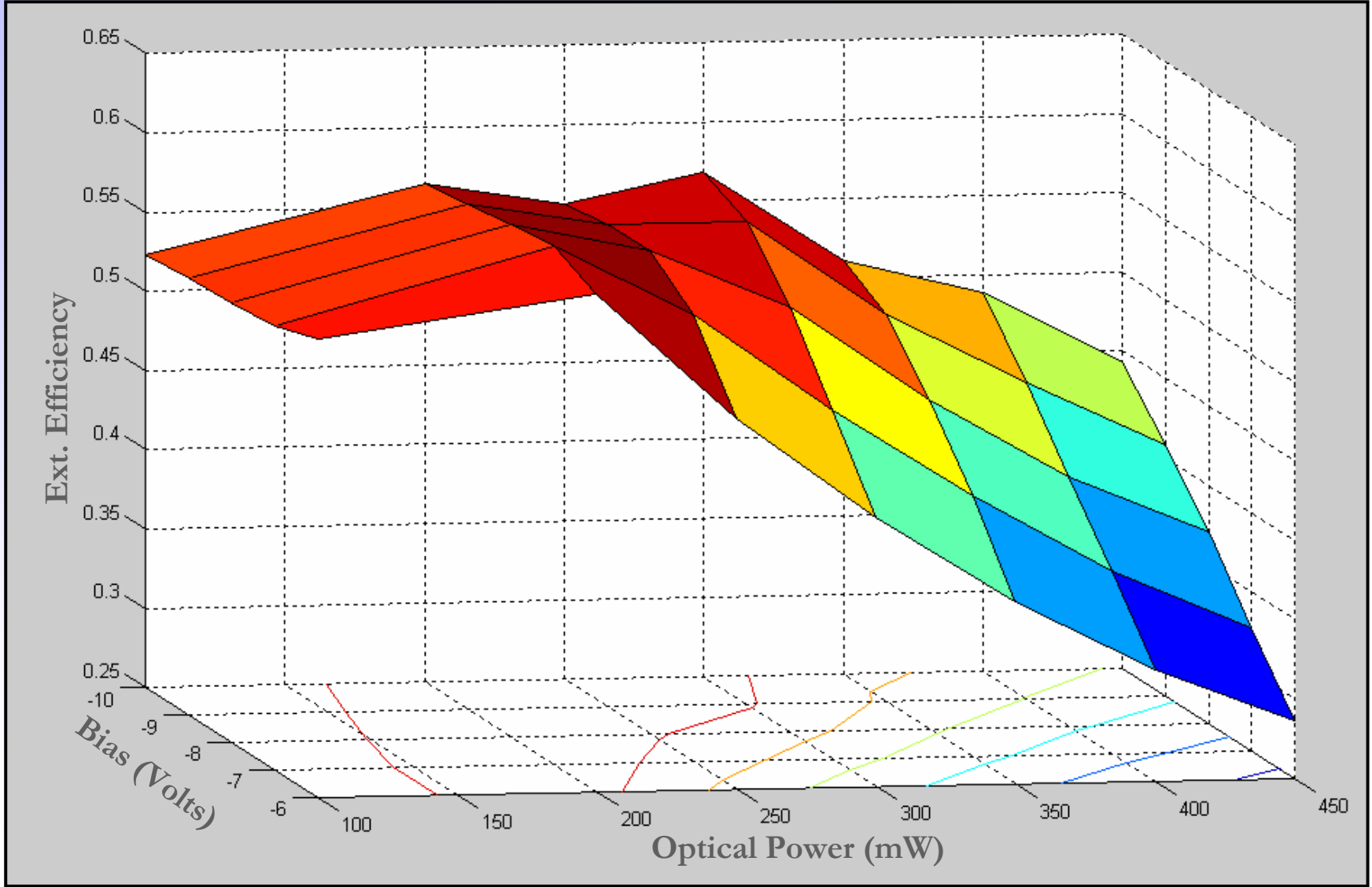
- Etc.



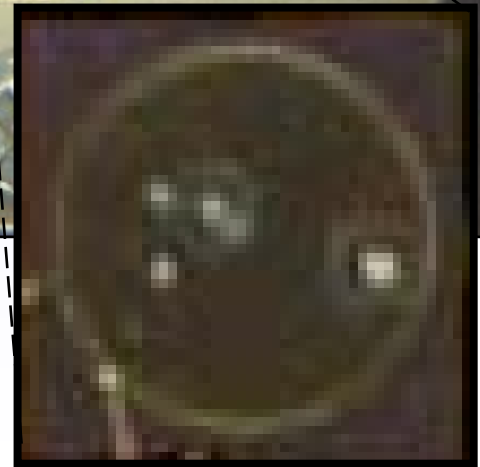
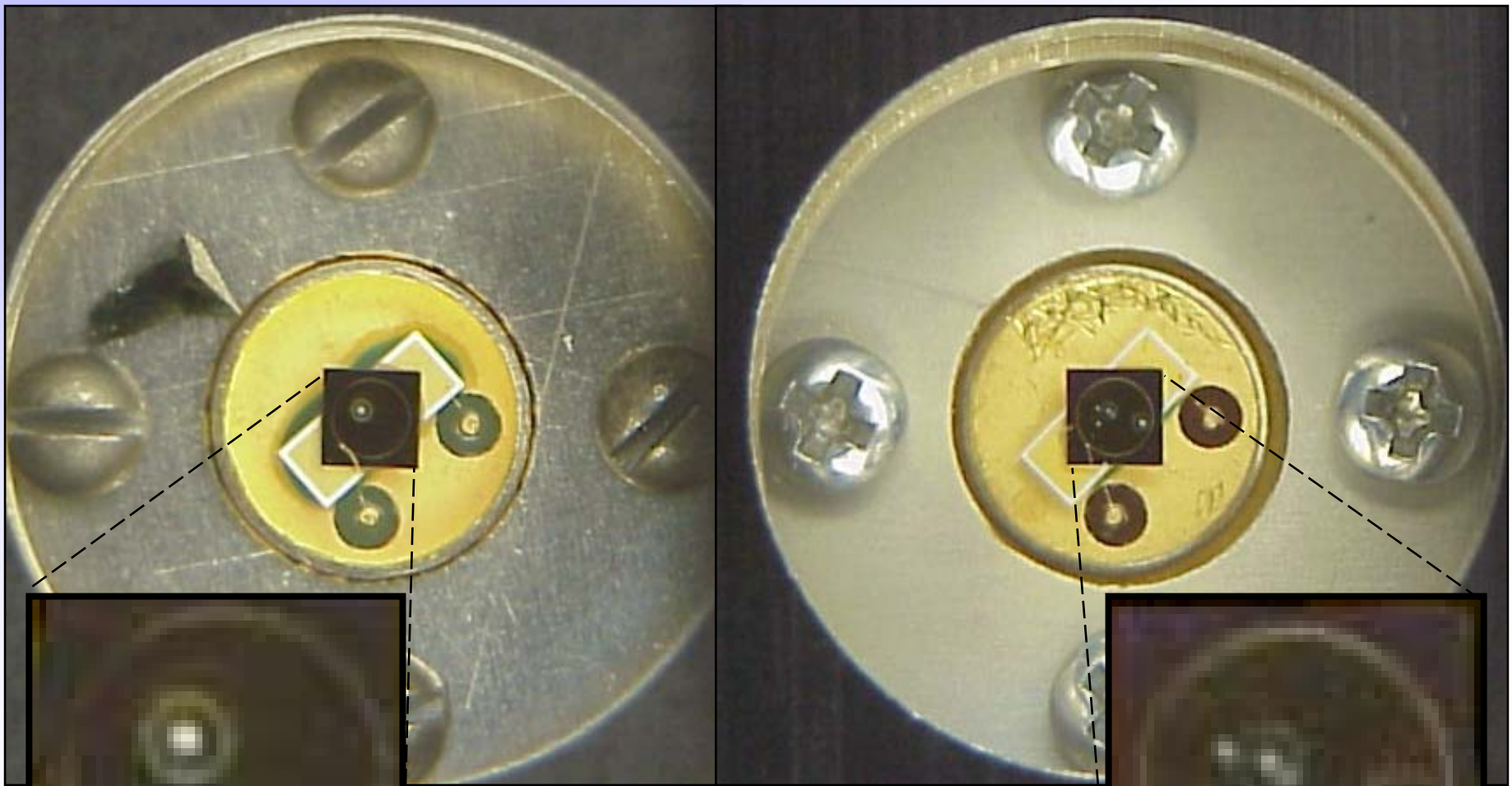
Device Internal Quantum Efficiency (Low Power ~ 50 mW)



External Quantum Efficiency – Thick Substrate

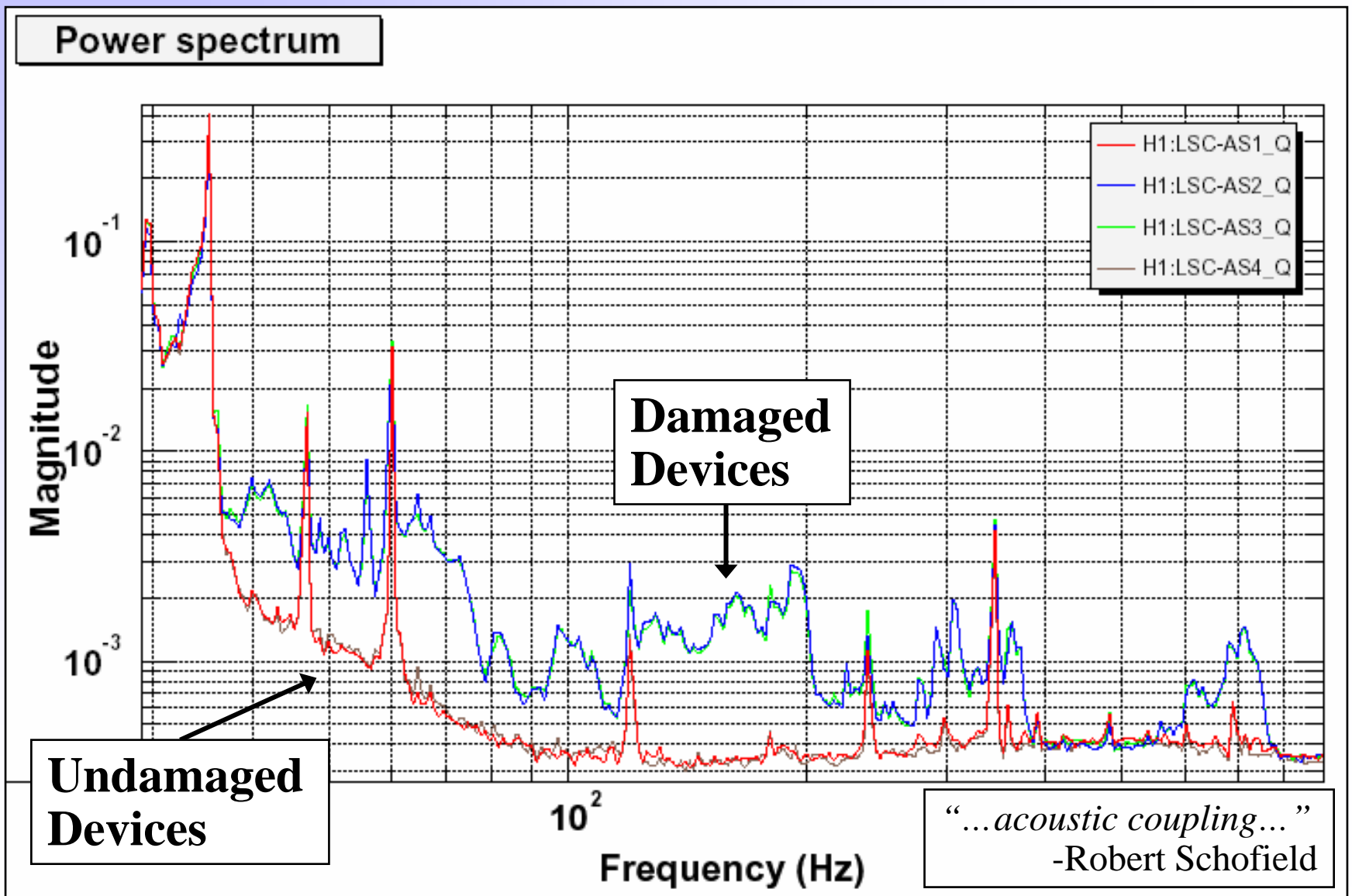


Damage Threshold – LLO Devices (9/23/03)

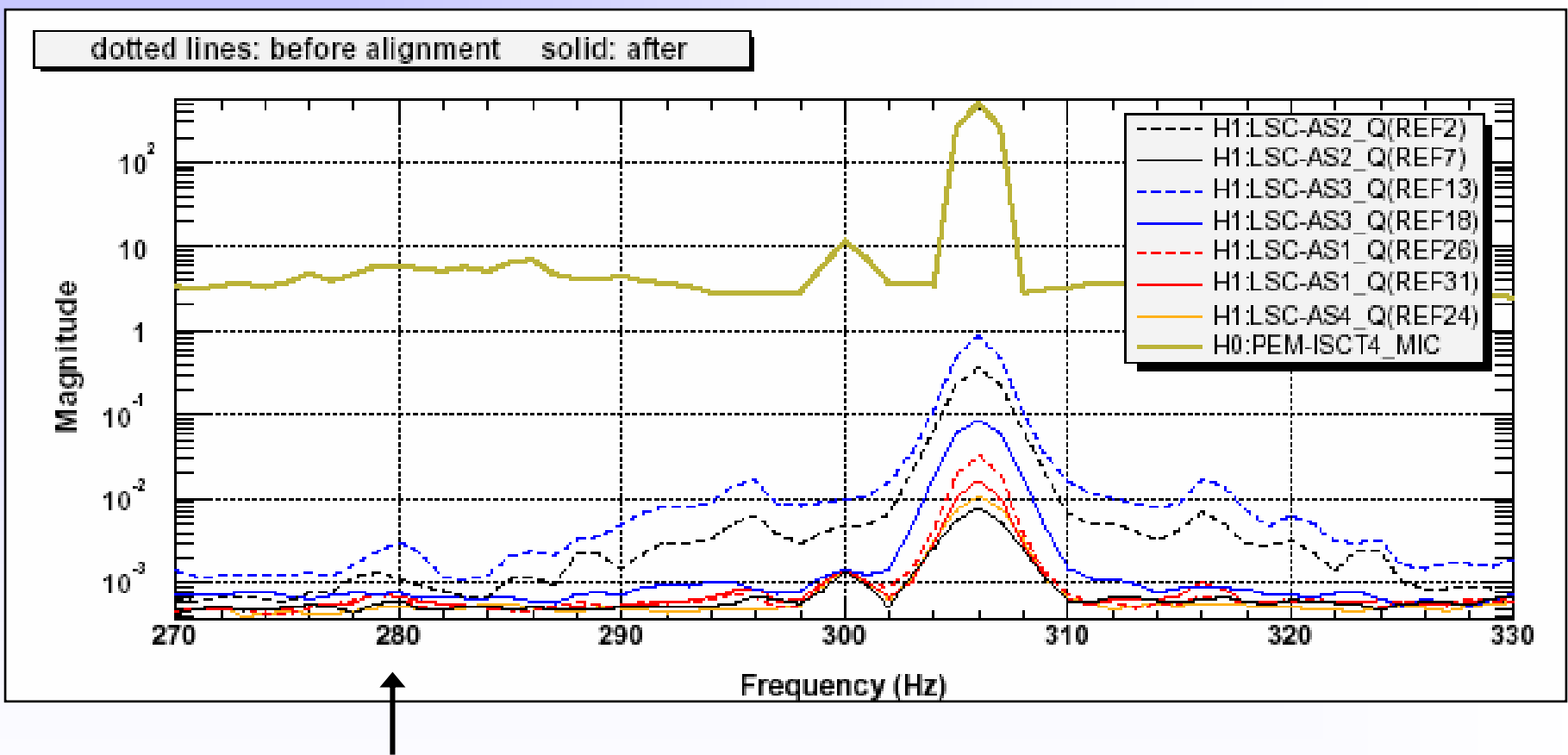


**$P > 2e6 \text{ W/cm}^2$ (???)
($>180 \text{ W}$ in $100 \mu\text{m}$ spot)**

LHO Damaged PDs – Shutter Problems (2/22/05)

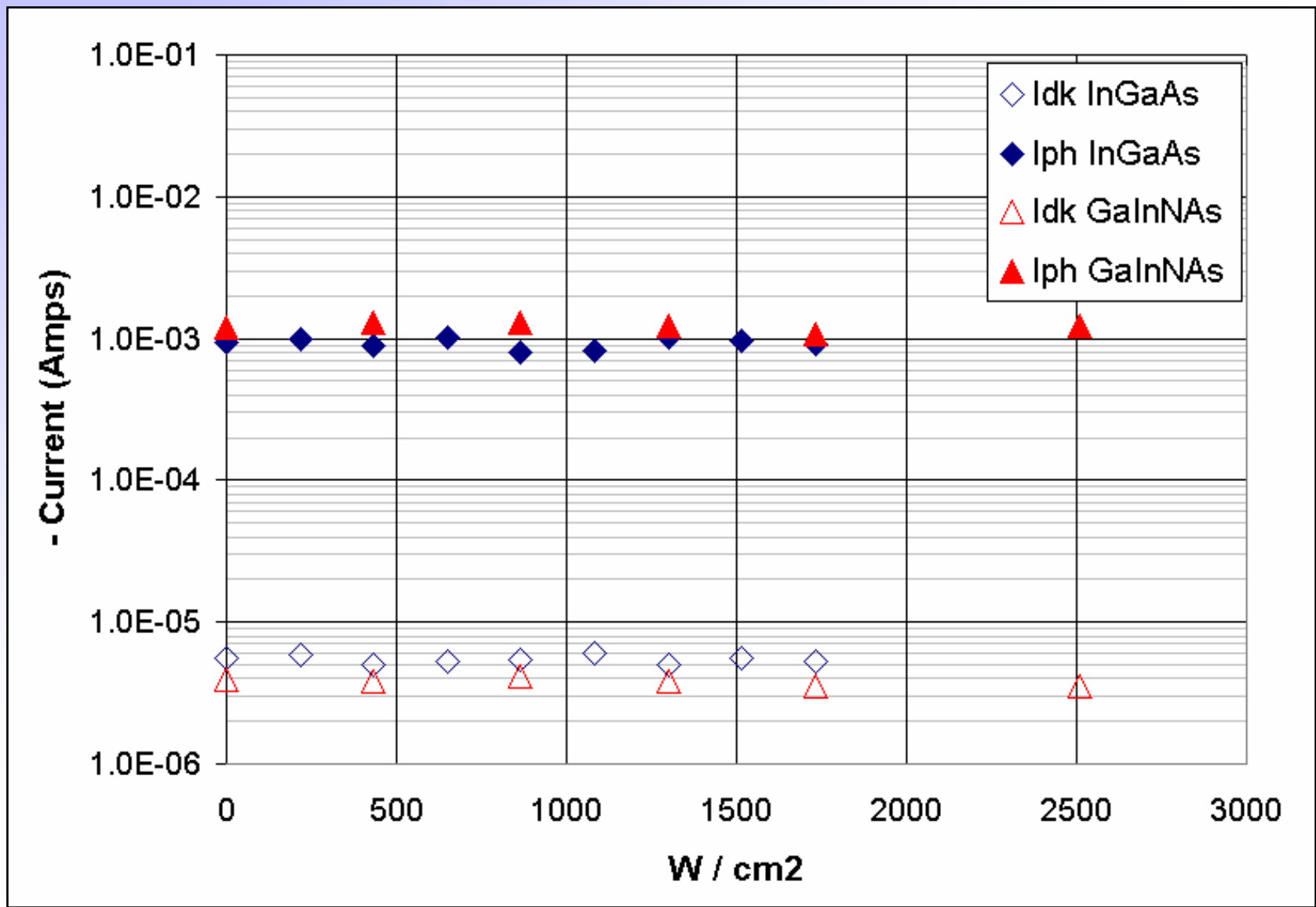


LHO Damaged PDs – Shutter Problems (2/18/05)

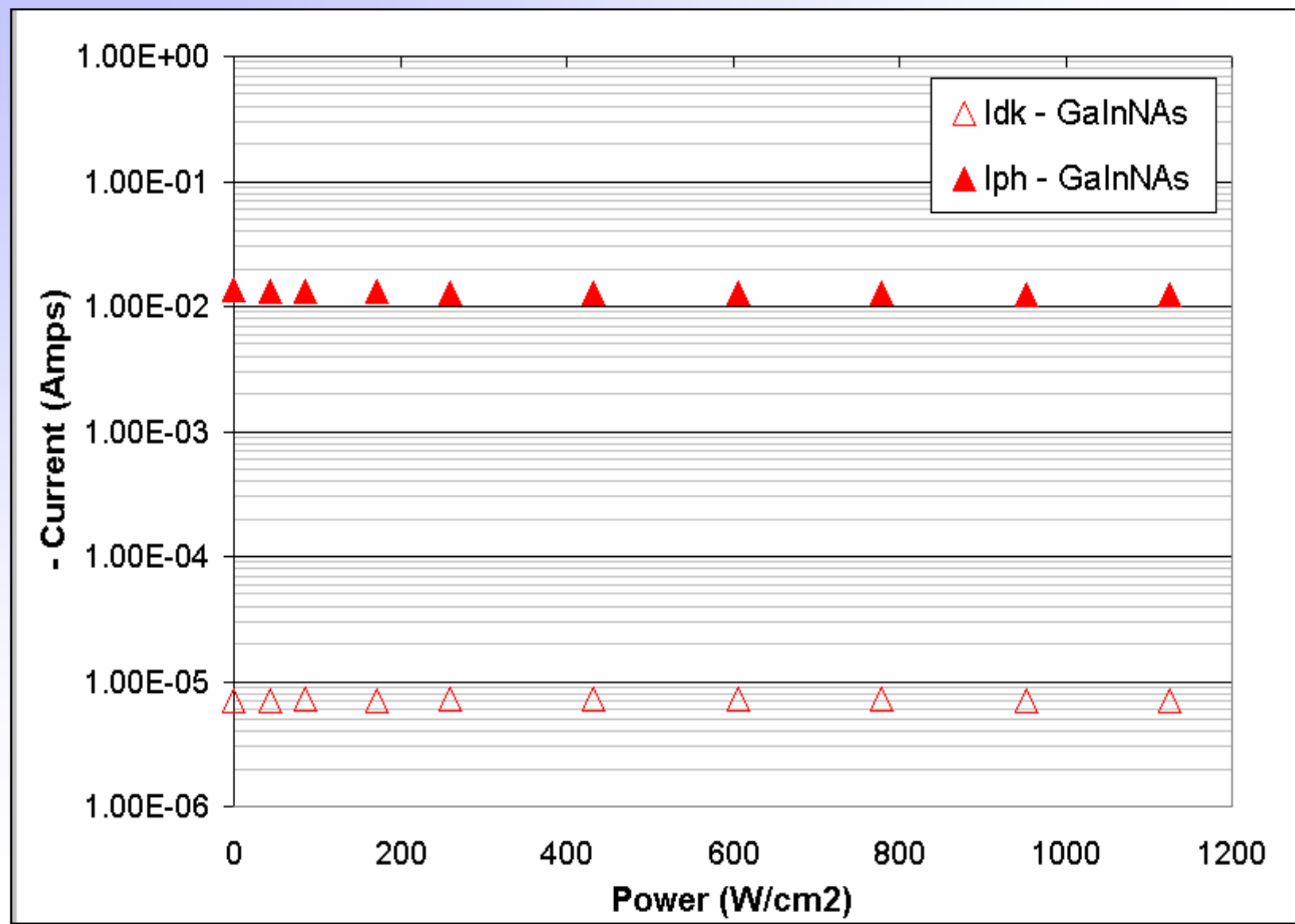


No injected Peak at 280 Hz

Rear-Illuminated Damage-Threshold Test



Front-Illuminated Damage-Threshold Test



Detector	Power Stabilization	Aux. Length Sensing	GW Channel
Diameter	3 mm	1.5 mm	1 mm (or larger?)
Steady-State Power	300 mW	100 mW	50 mW
3-dB 1/RC Bandwidth	5 MHz	30 MHz (→ 180 MHz?)	60 MHz
Quantum Efficiency	–	> 80 %	80 ~ 90 %
<i>Damage Threshold</i>	–	?	<i>Important?!</i>

AdLIGO Devices: Commercial Vendors



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<http://www.stanford.edu/~djackrel>

David Jackrel - Materials Science & Engineering - Microsoft Internet Explorer

	Material	mm Min	mm Max Dia	A / W Resp	% OE	Volts Rev Bias	mW Max Power	mA Max Linear
Electro-Optical Systems, Inc.	Germanium		5 10x10					
Germanium Power Devices Corp.	Germanium		1 10x10					
New Focus, Inc.	Germanium			5	0.50	58%	9	3
Onto-Electronics Inc.	Germanium		0.1					0.5
Electro-Optics Technology, Inc.	InGaAs	0.1		3	0.75	90%	6	low power
Electro-Optical Systems, Inc.	InGaAs		3	5				
Elekon Industries USA, Inc.	InGaAs	25um		3			18	
Fermionics Corp.	InGaAs	60um		5	0.65	75%		
Germanium Power Devices Corp.	InGaAs	0.5		5				
Hamamatsu	InGaAs	0.04	10		0.67	77%	1.0 - 10.0	6 (5mm dia) 100?
Elekon Industries USA, Inc.	InGaAs	25um	3				18	
Fermionics Corp.	InGaAs	60um	5	0.65	75%			
Germanium Power Devices Corp.	InGaAs	0.5	5					
Hamamatsu	InGaAs	0.04	10	0.67	77%	1.0 - 10.0	6 (5mm dia)	100?
International Light, Inc.	InGaAs		1				1.89W	
Microsemi	InGaAs	77??	20???	0.69	80%		20	
New England Photoconductor	InGaAs	40um	10	0.69	80%			
New Focus, Inc.	InGaAs	1	8	0.4 - 0.7	80%	9	50	
Onto-Electronics Inc.	InGaAs		0.3				5	
PerkinElmer, Inc.	InGaAs	0.5	5					
Precision Applied Science	InGaAs	80um	0.3	0.60	69%	15		
Thorlabs, Inc.	InGaAs	1	1	0.70	81%	12	100mW/cm2	1
UDT Sensors, Inc.	InGaAs	1	3	0.78	90%	2	low power?	20
Ultrafast Sensors	InGaAs	0.06x0.06						

- Substrate removal
- GaInNAs(Sb) growth (w/ upgraded system)
- ARC
- 1/f noise experiments

Successor - Zhilong Rao

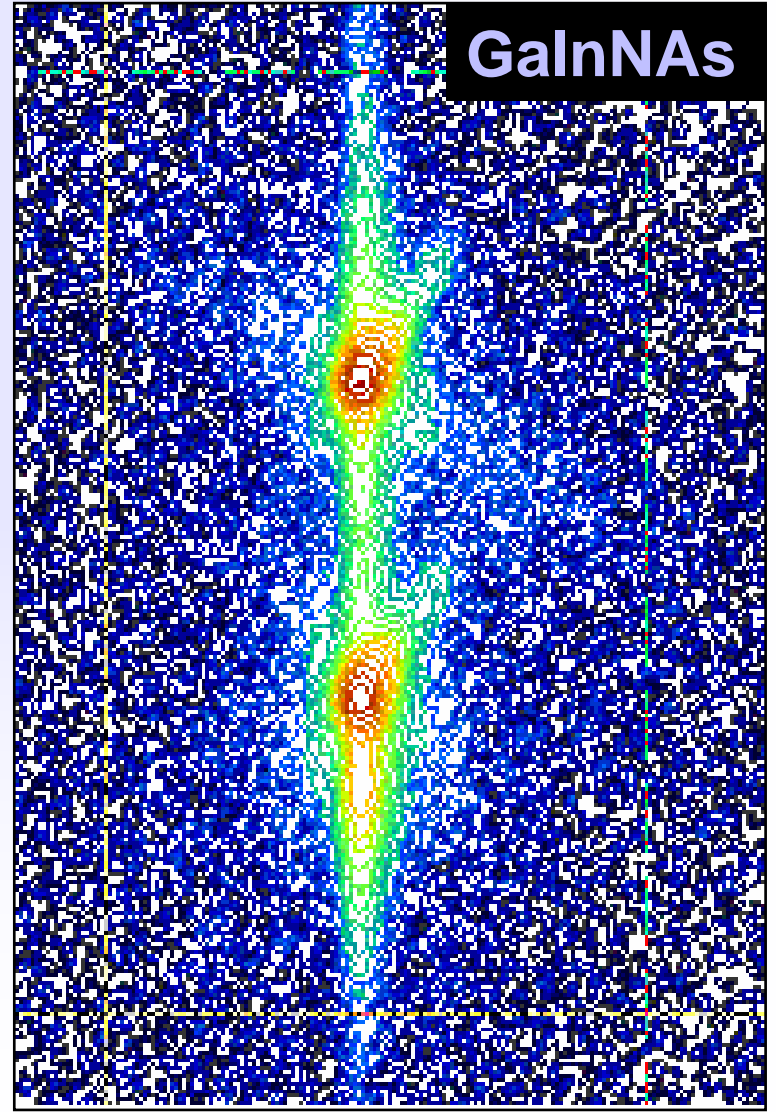
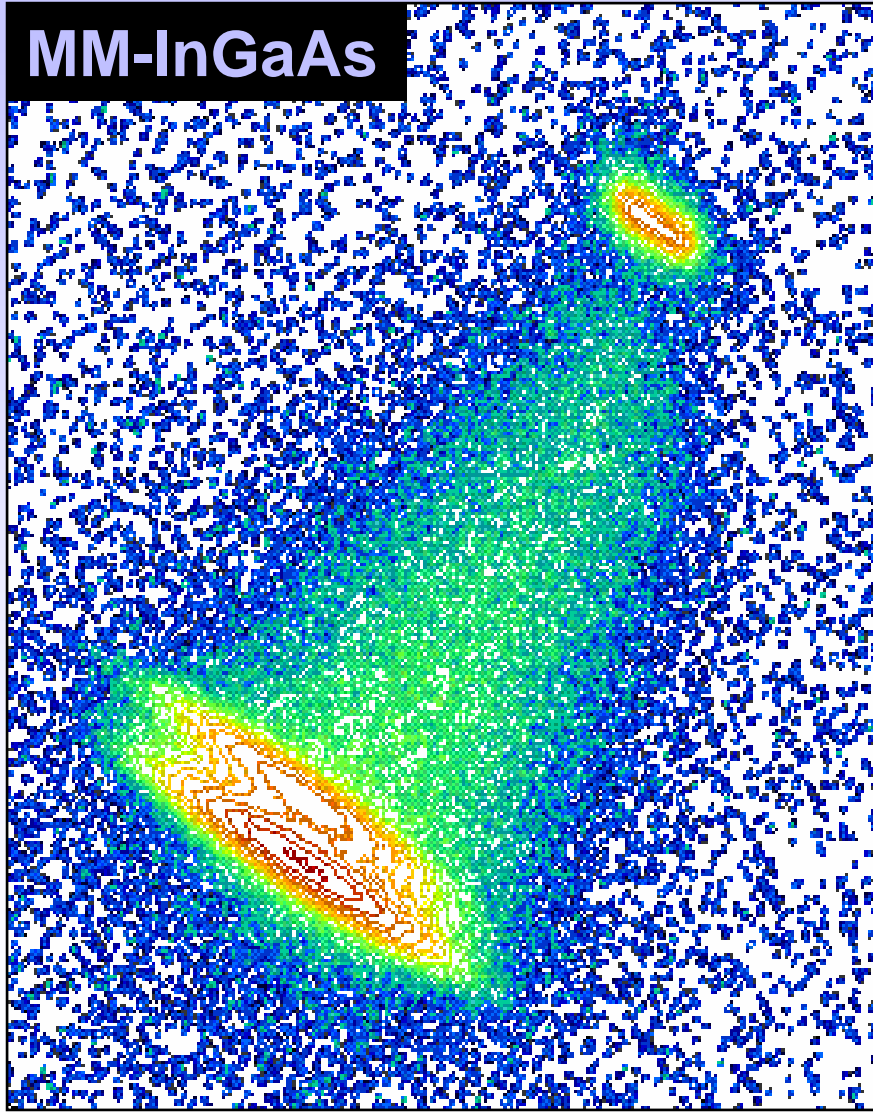
- Packaging devices / Testing components
- Higher saturation power? (→ RF detection?)
- Surface uniformity?, Backscatter?, etc.

Future Directions – What types of diodes are needed?

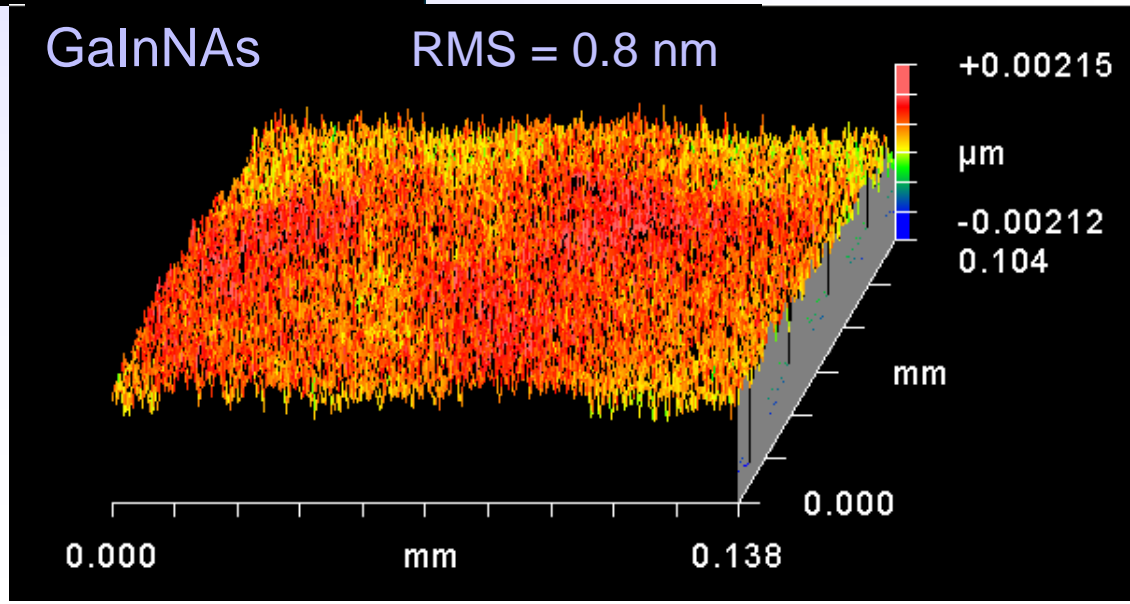
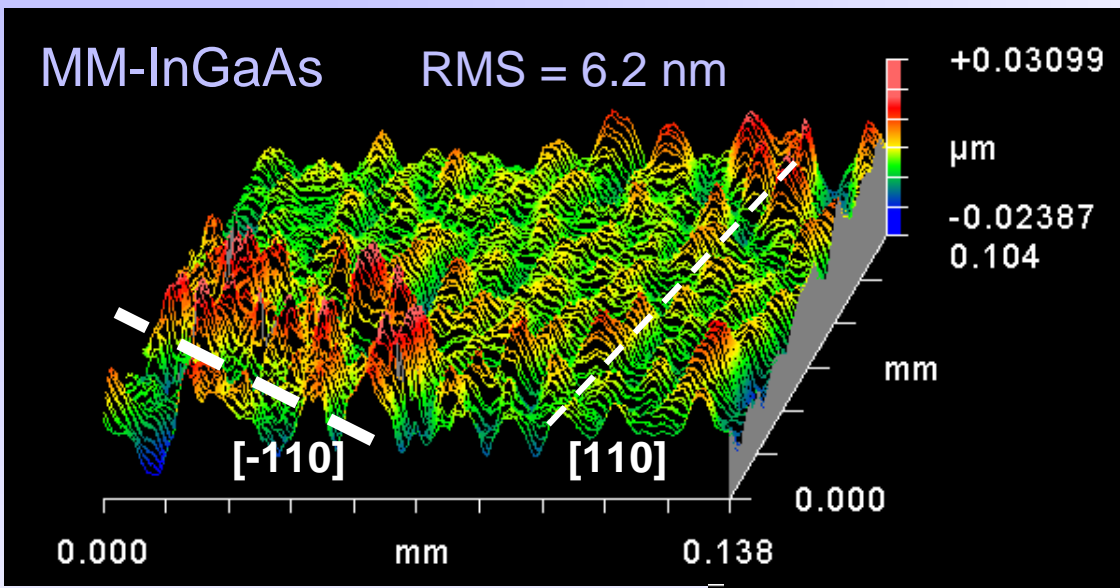


- Quantum Efficiency?
- Damage Threshold?
- Saturation Power?
 - RF detection
 - AdLIGO laser stabilization
- Electronic Noise?
 - DC
 - RF? (180 MHz)
- Frequency Response?
 - Commercially available?
- Other???

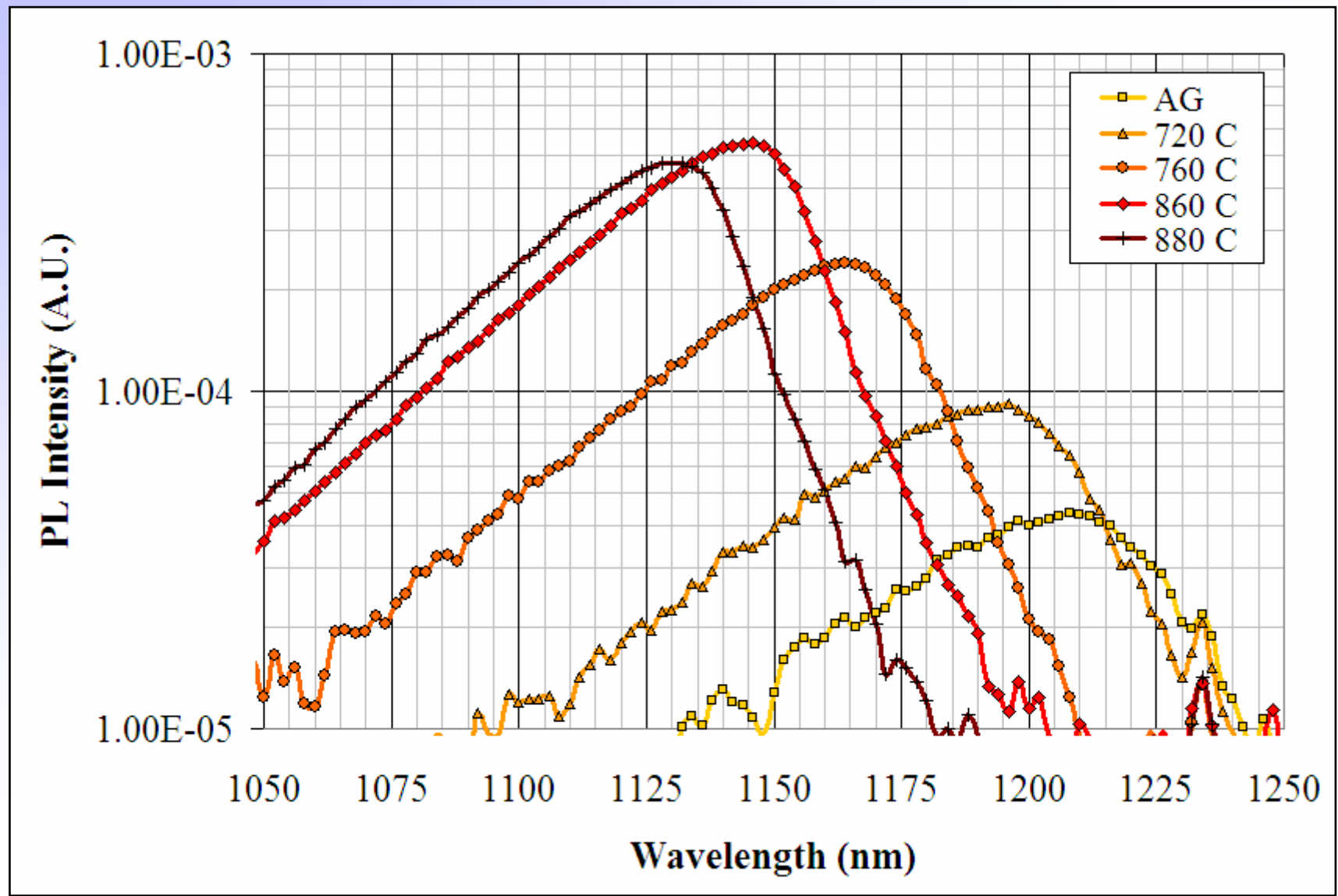
XRD Reciprocal Space Map (004)



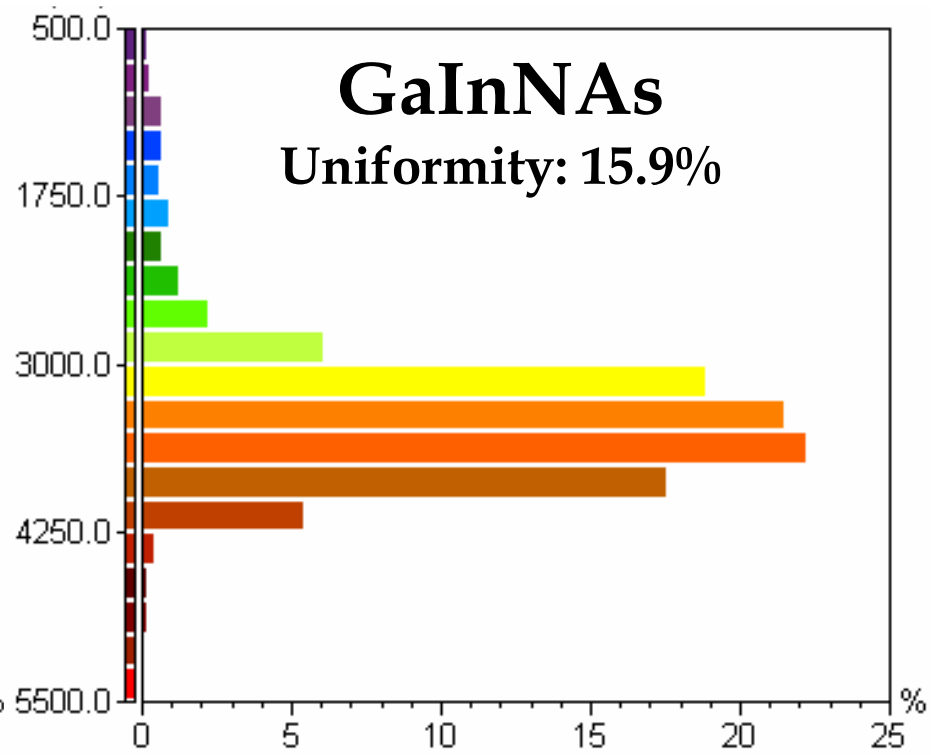
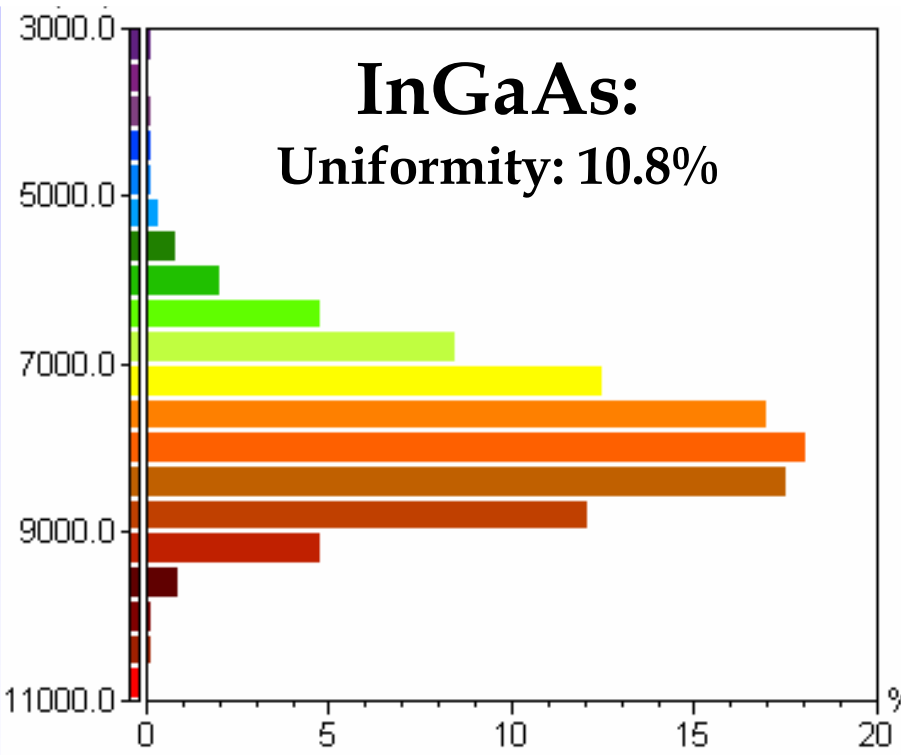
Surface Roughness



Optimizing Post-Growth Anneal

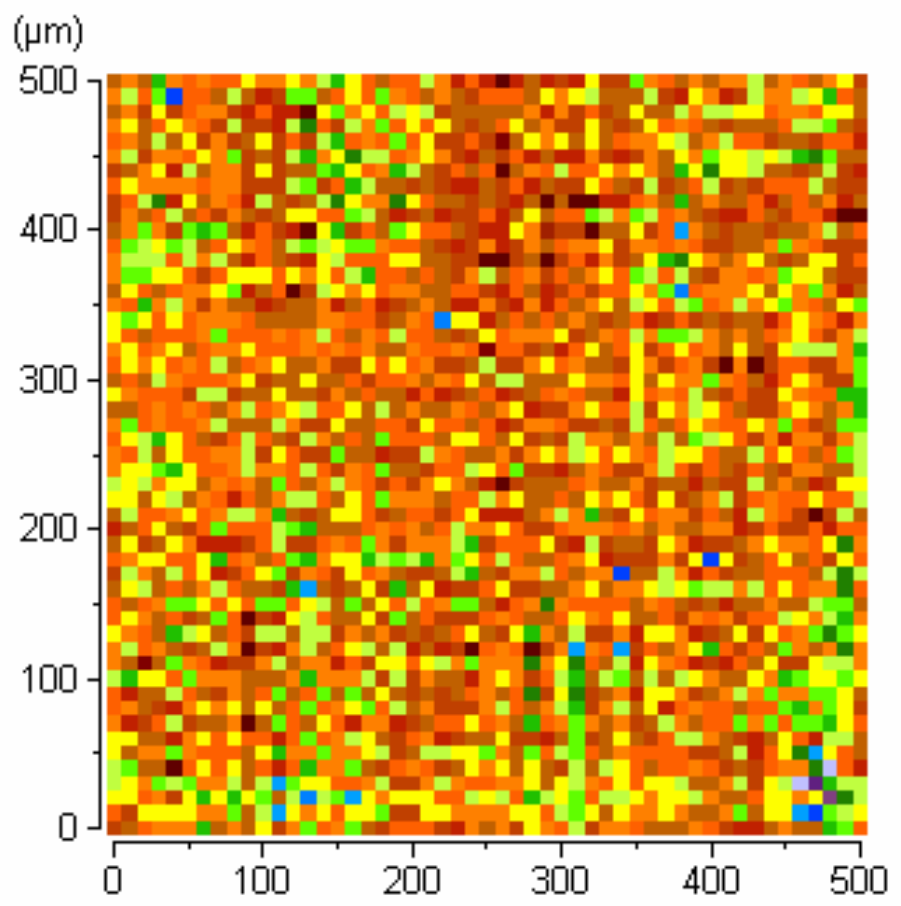


Scanning Photolumuminescence Intensity

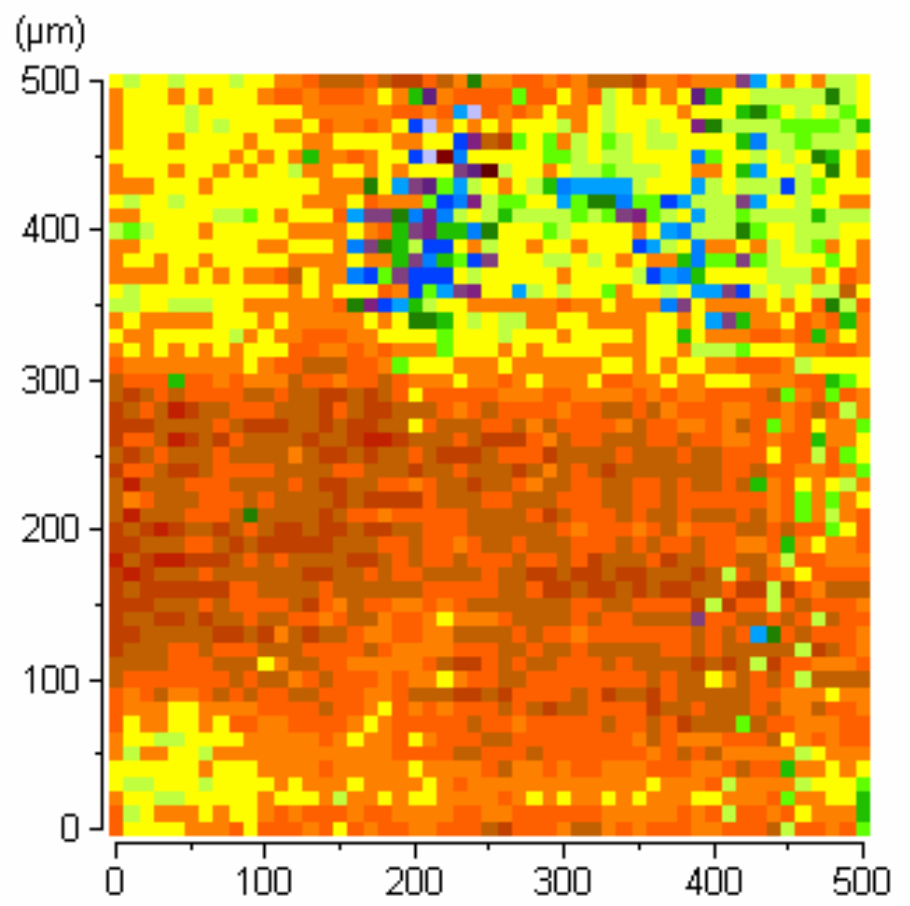


Scanning PL Intensity Maps

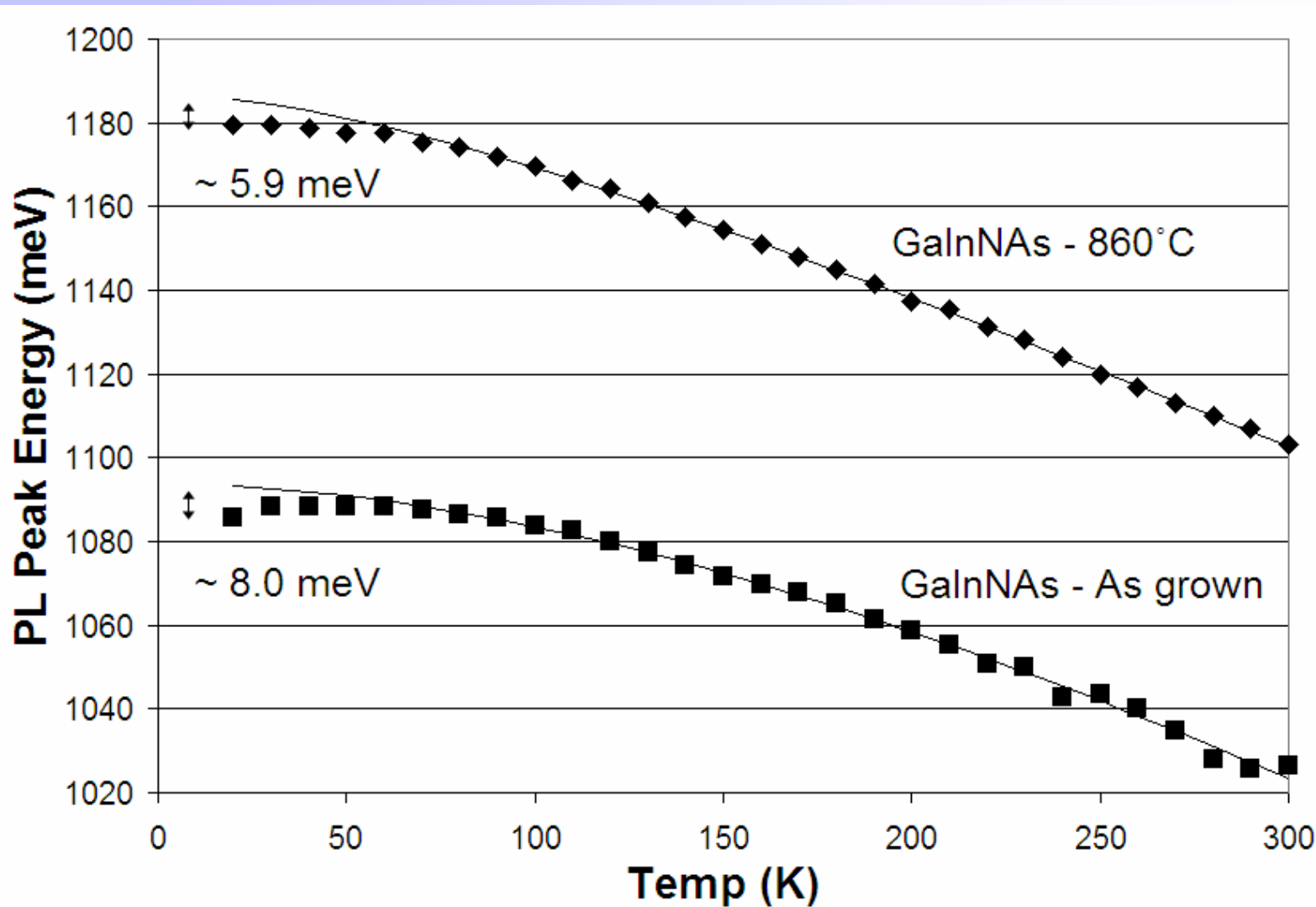
InGaAs



GaInNAs



GaNNAs Temp. Dependent PL: Localization Energy



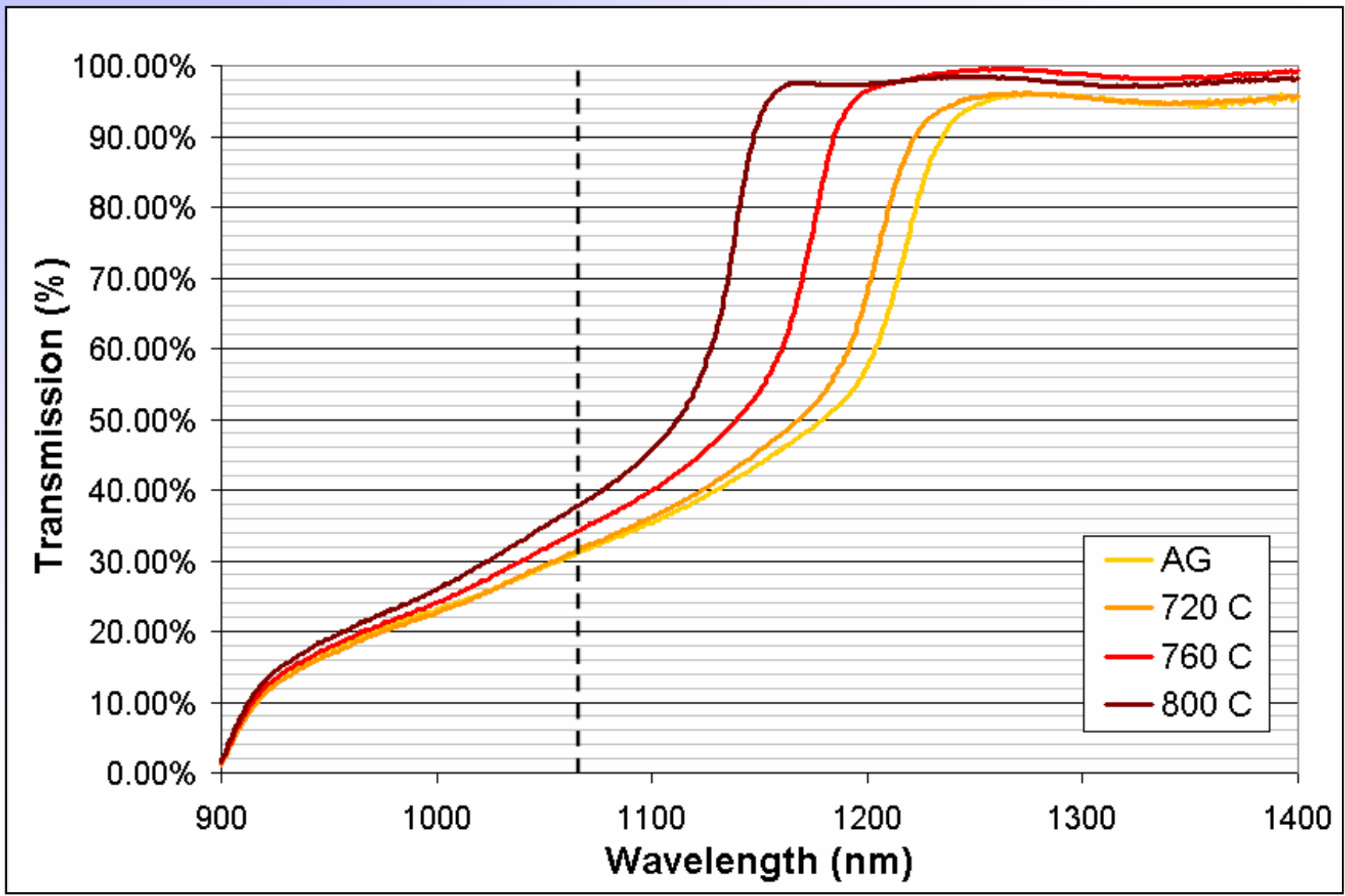
Deep Level Transient Spectroscopy

Majority Carrier Traps

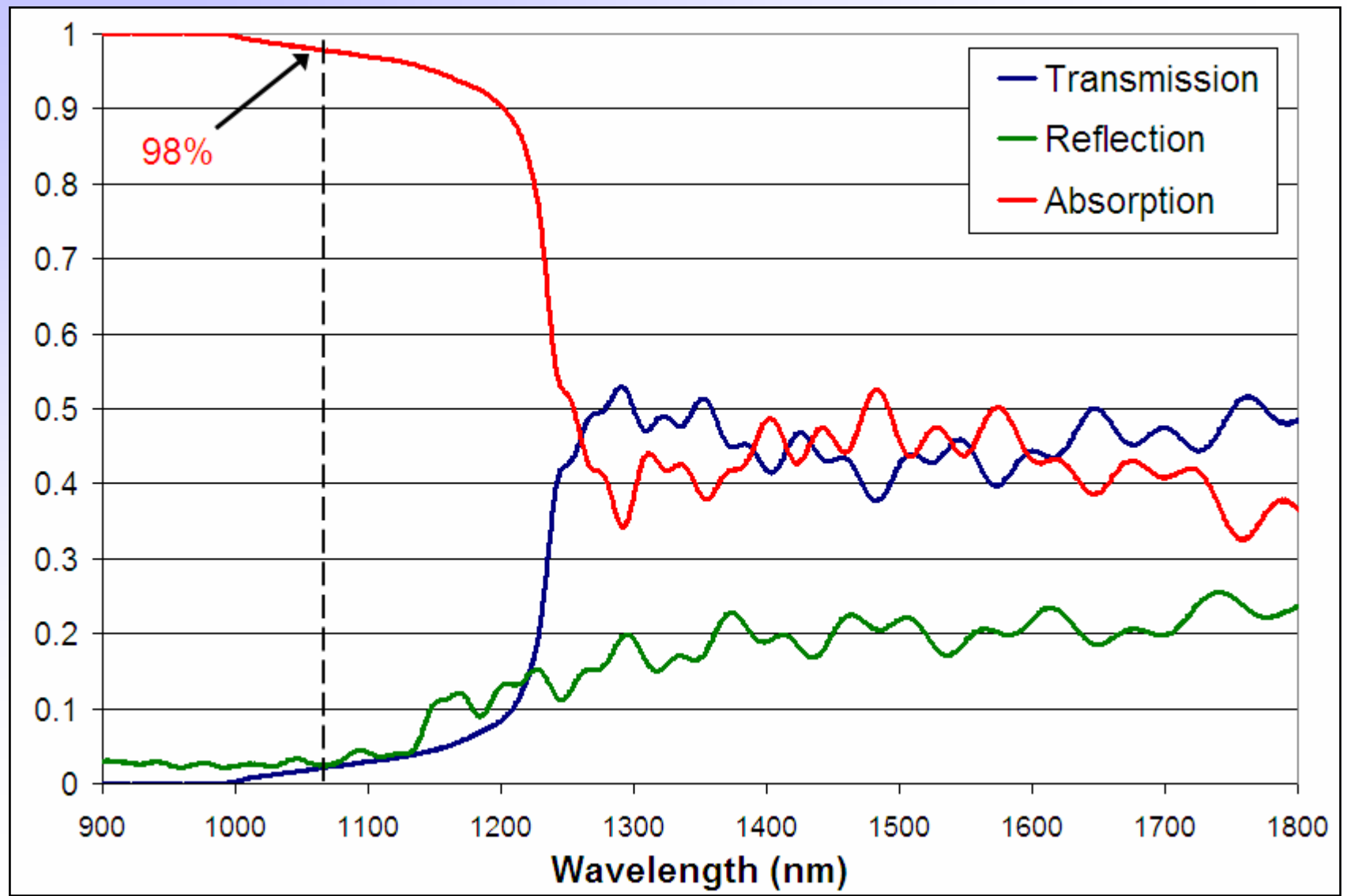


Sample	Activation Energy (eV)	Trap Density (cm ⁻³)	Capture Cross-Section (cm ²)
LM - GaInNAs	0.63	1.1 x 10 ¹⁴	9.0 x 10 ⁻¹⁵
	0.27	3.9 x 10 ¹³	2.5 x 10 ⁻¹⁶
	0.22	7.5 x 10 ¹³	3.2 x 10 ⁻¹⁵
	0.15	1.7 x 10 ¹³	5.2 x 10 ⁻¹⁸
MM - InGaAs	0.47	2.0 x 10 ¹³	4.9 x 10 ⁻¹⁵
	0.12	3.1 x 10 ¹²	3.2 x 10 ⁻¹²

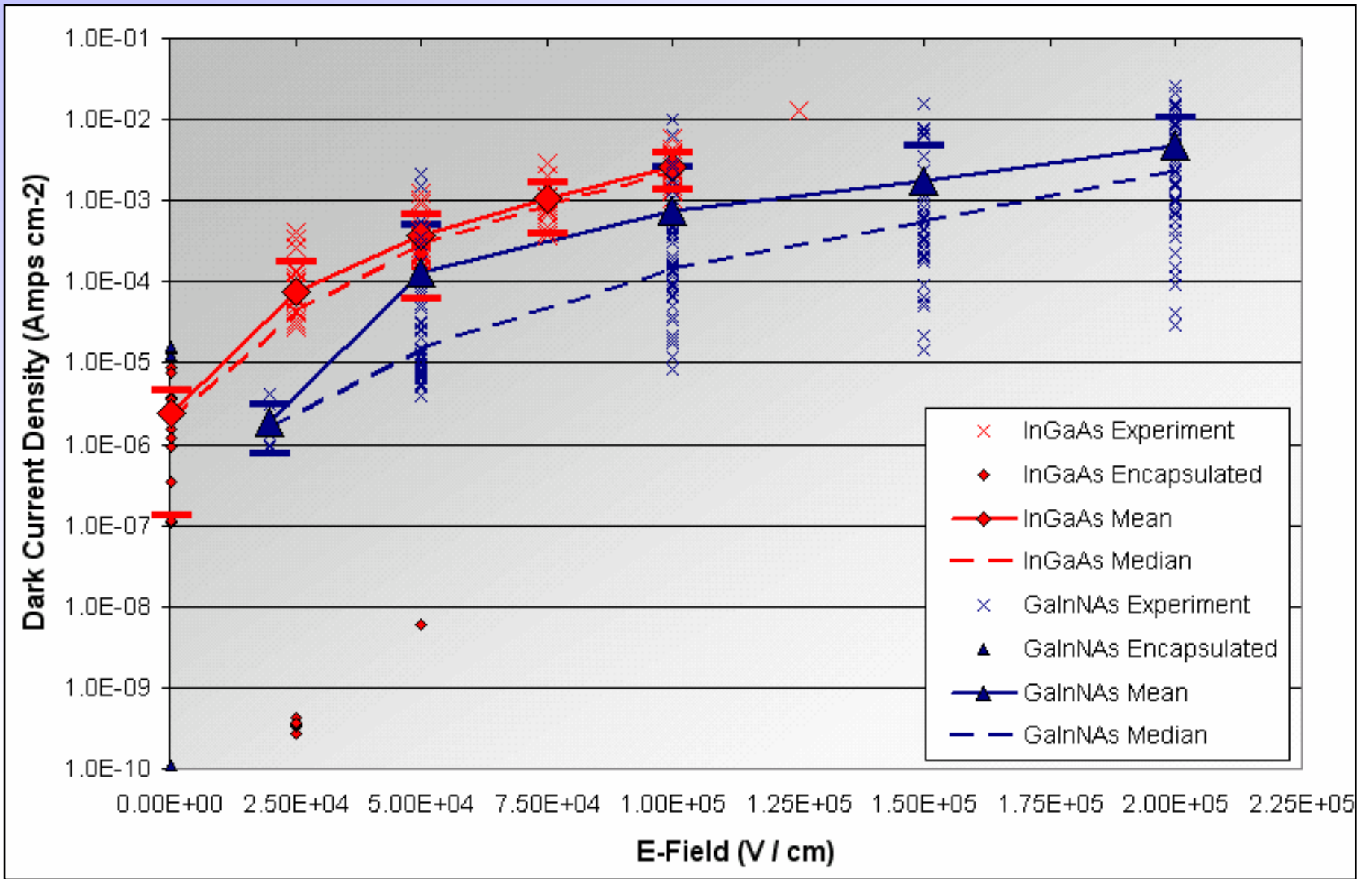
1 μm GaInNAs Film Transmission



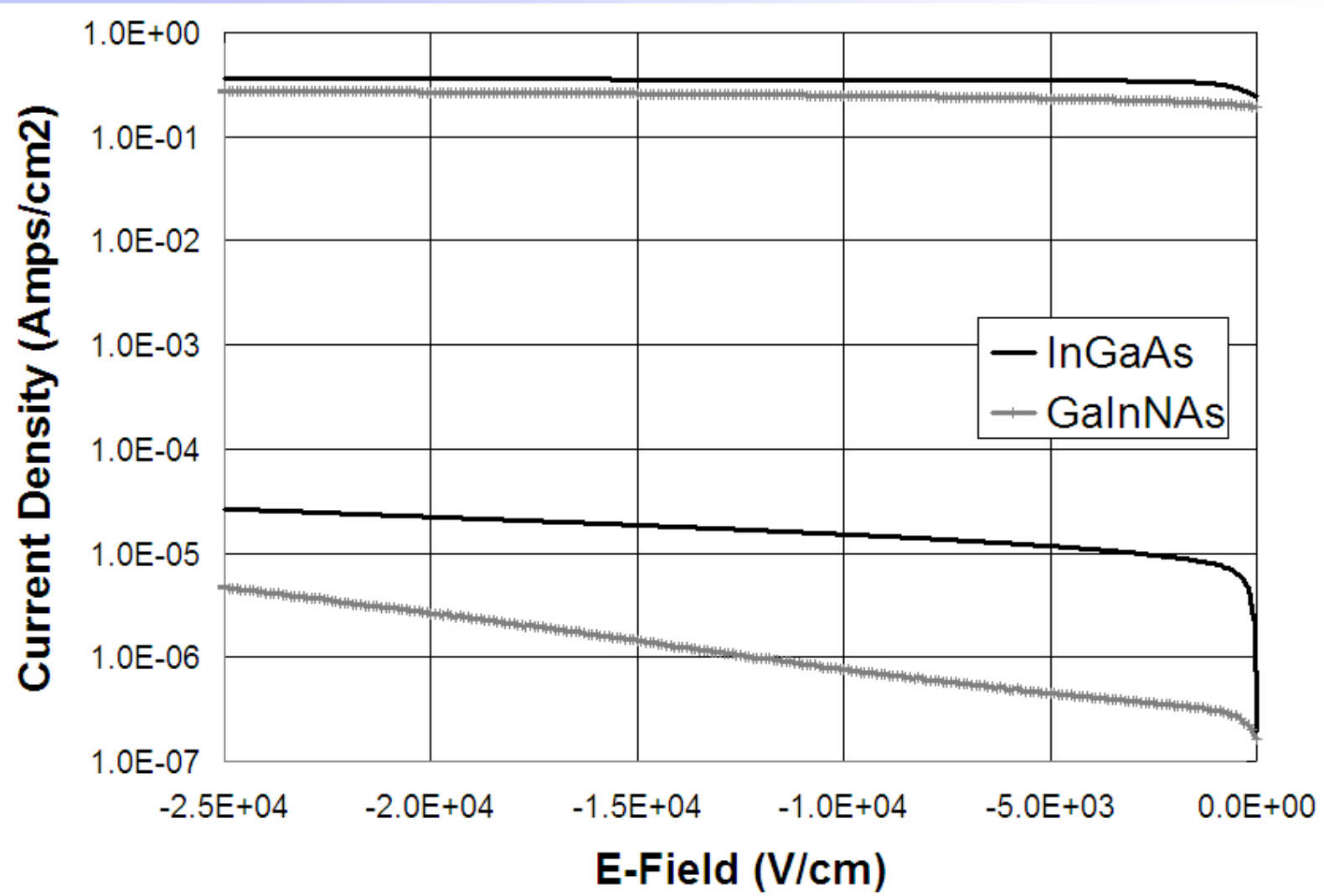
2 μm InGaAs Absorption Spectrum



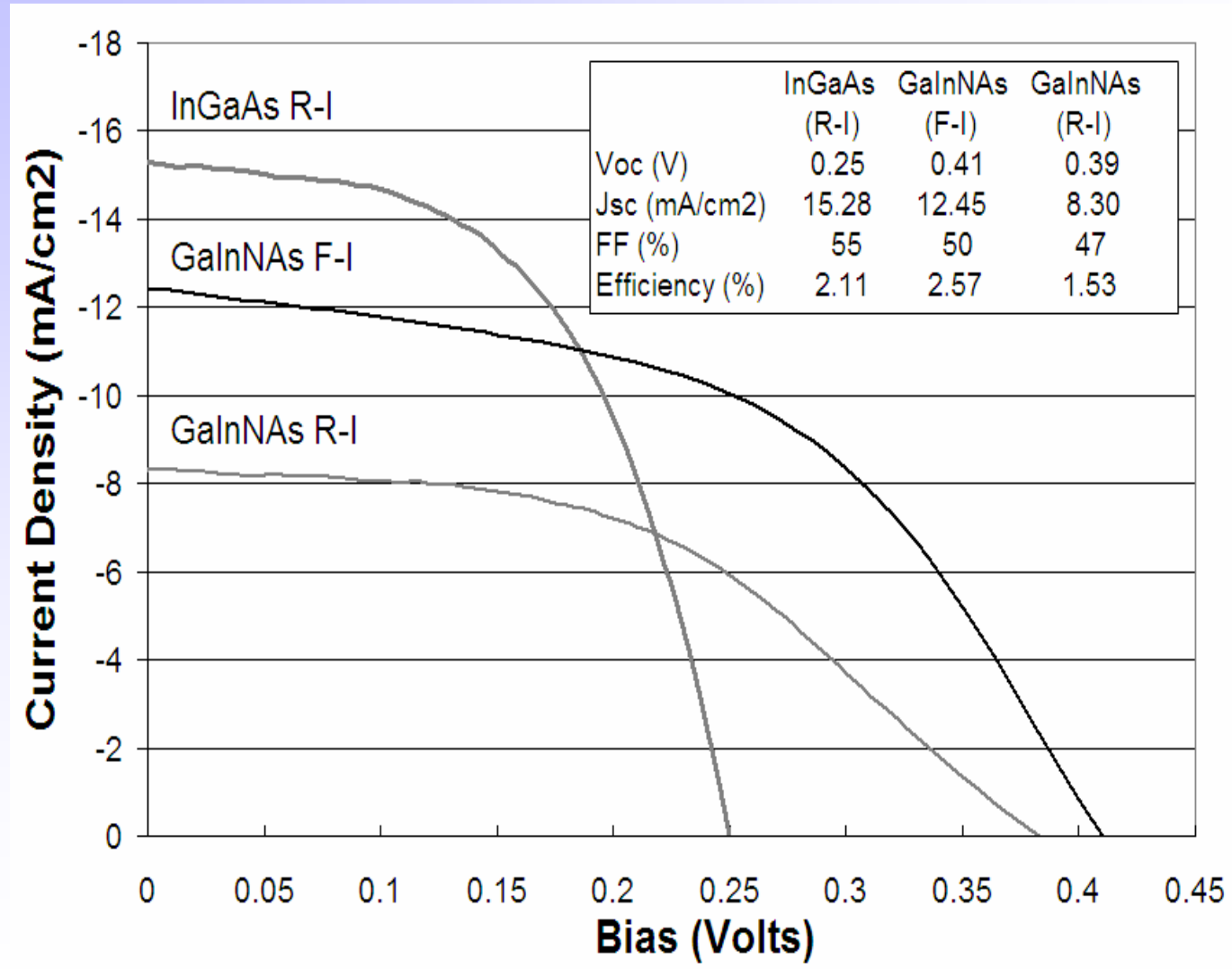
InGaAs vs. GaInNAs Dark I Density



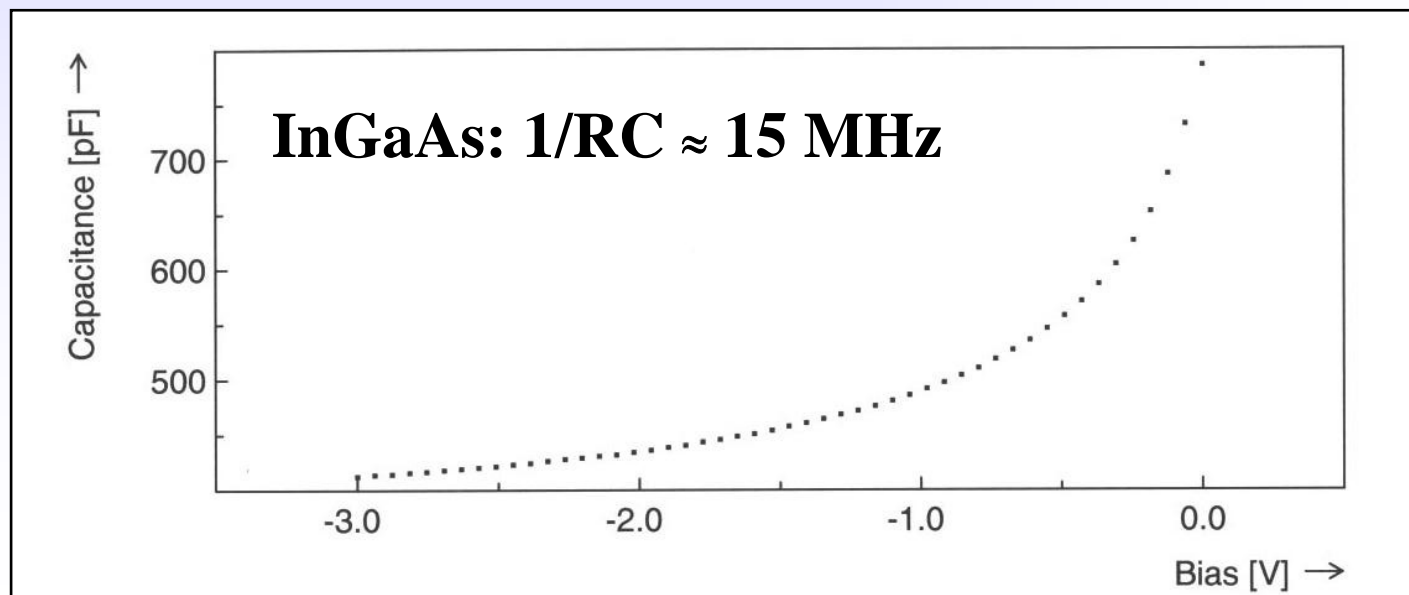
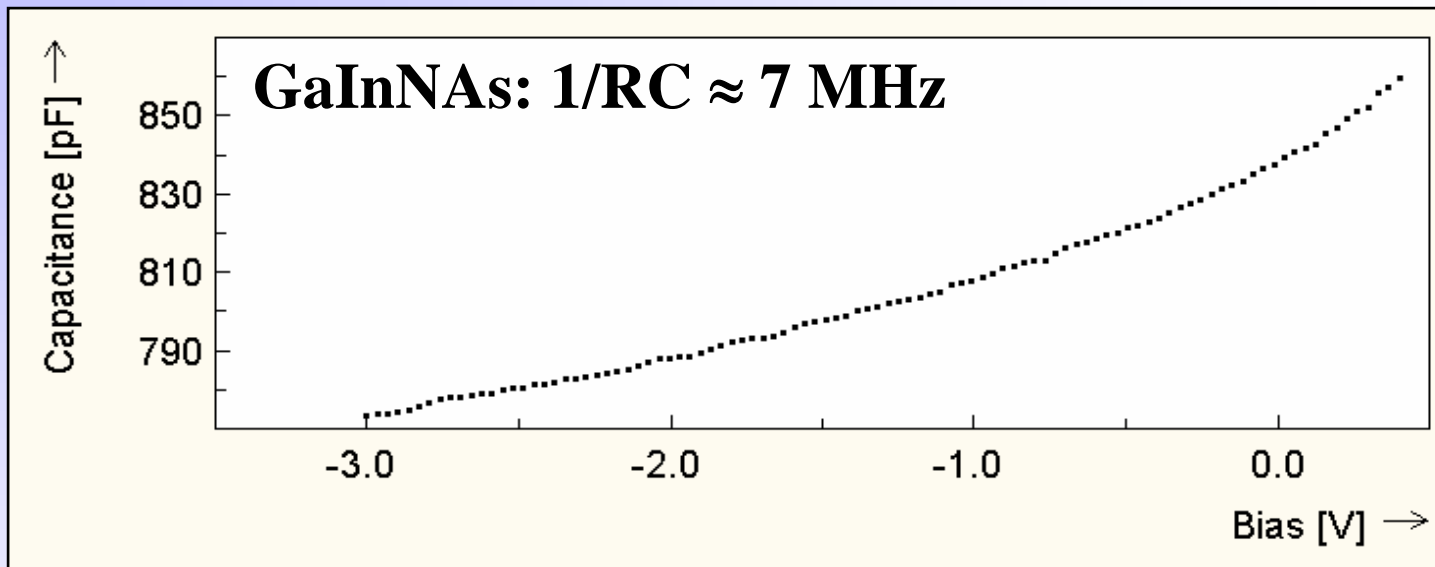
Dark and Photocurrent (SNR)



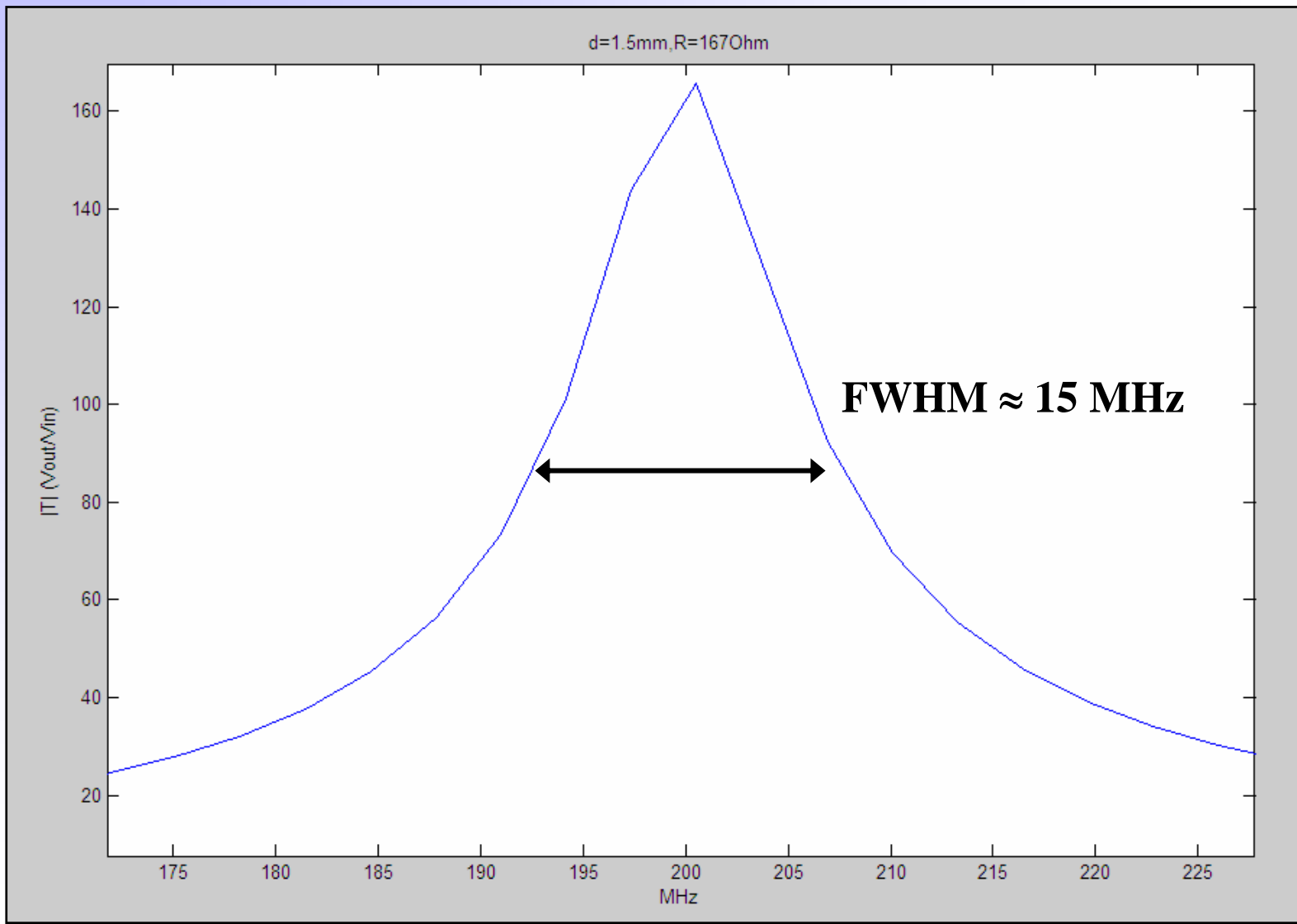
Photovoltaic Response



C-V Curves



LCR Resonant Circuit Modeling



LIGO 1

power in each arm (W)	ITM transmission	Total Power on AS-PD	Spot Radius (um)	Area (cm ²)	Power Density (W/cm ²)
6000	0.03	360	5.00E+01	7.85398E-05	4.58E+06
6000	0.03	180	5.00E+01	7.85398E-05	2.29E+06
		20	1.178511302	4.36E-06	4.58E+06
		20	1.666666667	8.73E-06	2.29E+06

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power in each arm (W)	ITM transmission	Total Power on AS-PD	Spot Radius (um)	Area (cm ²)	Power Density (W/cm ²)
8.30E+05	0.03	4.98E+04	5.00E+01	7.85398E-05	6.34E+08
		20	0.100200602	3.15E-08	6.34E+08